

<b>INFORMATION DISCLOSURE STATEMENT</b> <b>BY APPLICANT</b>		Docket: 1011-59137	App: 10/039,934
		Applicant: Mohammed Ali AbdEl-Halim AbdEl-Wahid	
		Filed: October 26, 2001	Art Unit: 2133



**U.S. PATENT DOCUMENTS**

Init.*	Number	Date	Name	Class	Sub	Filed
<i>MJ</i>	4,503,537	3/1985	McAnney	—	—	
<i>MJ</i>	5,481,471	1/1996	Naglestad et al.	—	—	
<i>MJ</i>	6,005,407	12/1999	Arabi et al.	—	—	
<i>MJL</i>	6,202,183	3/2001	Ginetti et al.	—	—	

**OTHER DOCUMENTS**

<i>MJ</i>		Fluence Technology Inc., "BISTMaxx™ Product Catalog," 38 p. (September 2000)
<i>MJ</i>		Texas Instruments, "IEEE Std 1149.1 (JTAG) Testability Primer," 146 p. (1997)
<i>MJ</i>		LogicVision, "LogicVision - PLL BIST," 1 p. (downloaded from <a href="http://www.logicvision.com/products/pll.html">http://www.logicvision.com/products/pll.html</a> on April 10, 2001)
<i>MJ</i>		Chatterjee and Nagi, "Design for Testability and Built-In Self-Test of Mixed-Signal Circuits: A Tutorial," <i>IEEE 10th Int'l Conference on VLSI Design</i> , pp. 388-92
<i>MJ</i>		Wey, "Mixed-Signal Circuit Testing -- A Review," <i>Third Int'l Conference on Electronics, Circuits and Systems</i> , pp. 1064-67 (1996)
<i>MJ</i>		Lin et al., "Automatic BIST Design Tool for Mixed-Signal Circuits," <i>AUTOTESTCON '98: IEEE Systems Readiness Technology Conference</i> , 97-102 (1998)
<i>MJ</i>		Lubaszewski et al., "Design of Self-Checking Fully Differential Circuits and Boards," <i>IEEE Transactions on VLSI Systems</i> , vol. 8, no. 2, pp. 113-28 (April 2000)

RECEIVED  
MAY 01 2002  
Technology Center 2100

<b>INFORMATION DISCLOSURE STATEMENT</b> <b>BY APPLICANT</b>			Docket: 1011-59137	App: 10/039,934
			APR 29 2002 JC2A PATENT & TRADEMARK OFFICE	
			Applicant: Mohammed Ali AbdEl-Halim AbdEl-Wahid	
			Filed: October 26, 2001	Art Unit: 2133
<i>MJ</i>			"IEEE Standard for a Mixed-Signal Test Bus," <i>IEEE Std. 1149.4</i> , 84 pp. (2000)	
			"IEEE Standard Test Access Port and Boundary-Scan Architecture," <i>IEEE Std. 1149.1-1a</i> , 172 pp. (1993)	
			Nicolaidis & Zorian, "Scaling Deeper to Submicron: On-Line Testing to the Rescue," <i>IEEE Proceedings of the Design, Automation and Test in Europe Conference and Exhibition</i> , 1 p. (1999)	
			Milor, "A Tutorial Introduction to Research on Analog and Mixed-Signal Circuit Testing," <i>IEEE Transactions on Circuits and Systems-II: Analog and Digital Signal Processing</i> , vol. 45, no. 10, pp. 1389-1407 (October 1998)	
EXAMINER:	<i>John J. Trivis</i>		DATE	<i>5/25/04</i>
*Examiner: Initial if considered, whether or not in conformance with MPEP 609; draw line through cite if not in conformance and not considered. Send copy.				

BEST AVAILABLE COPY